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PHOTO-DOUBLE DETACHMENT OF F⁻ and Cl⁻ IONS. A. AGUILAR¹, J. THOMPSON, U. Nevada, Reno, NV, D. CALABRESE, Sierra College, Rocklin, CA, A. COVINGTON, LTCC, Lake Tahoe, CA, C. CISNEROS, CCF-UNAM, Cuernavaca, Mexico, V. DAVIS, USMA, West Point, NY, M. GULLEY, LANL, Los Alamos, NM, M. HALKA, Embry-Riddle Aeronautical U., Prescott, AZ, D. HANSTORP, J. SANDSTRÖM, Chalmers U., Göteborg, Sweden, B. MCLAUGHLIN, Queen's U., Belfast, UK, D. PEGG, U. Tennessee, Knoxville, TN — We have measured absolute cross sections for the photo-double detachment of F⁻ and Cl⁻ ions. The measurements were made over the energy ranges of 20-60 eV and 18-42 eV, respectively. The experiment was performed at the Photo-Ion-Beam endstation[1] of beamline 10.0.1 at the Advanced Light Source at LBNL. The beams of halogen negative ions from an accelerator were merged co-axially with the beam of EUV photons. The measured cross sections will be compared with recent R-matrix calculations. [1] A.M.Covington et al. Phys. Rev. A 66, 062710 (2002)

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Prefer Oral Session
 Prefer Poster Session

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